

Notice of References Cited	Application/Control No. 09/923,810	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0130324	09-2002	SONG et al.	257/72
	B	US-2003/0085404	05-2003	Kim et al.	257/72
	C	US-6,081,308	06-2000	Jeong et al.	349/42
	D	US-6,433,842	08-2002	Kaneko et al.	349/43
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 4-240824	08-1992	Japan	Dojiro et al	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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